

Room-temperature multiferroic behavior in layer-structured Aurivillius phase ceramics

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ABSTRACT

M

... H ... A ...
 ... D ... H ... A ... $B_{5.25}L_{0.75}F_2C_3O_{18}$...
 ... A ... *in situ* ...
 $F^{3+} O F^{3+}, C^{3+} O C^{3+}, F^{3+} O C^{3+}$...
 ... A ... C / F ...

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M (FM) (FE) ... $B_5F_3O_{15}$ (= 4) $B_6F_2_3O_{18}$...
 ... $B_4_3O_{12}$... $B_5F_{0.5}C_{0.5}_3O_{15}$...
 ... $(B_2O_2)^{2+}(A_{-1}B O_3 +1)^{2-}$ (A ... $^{14,15} H$...
 ... 16 ...
 B- $B F O_3$... 7,11 ... A

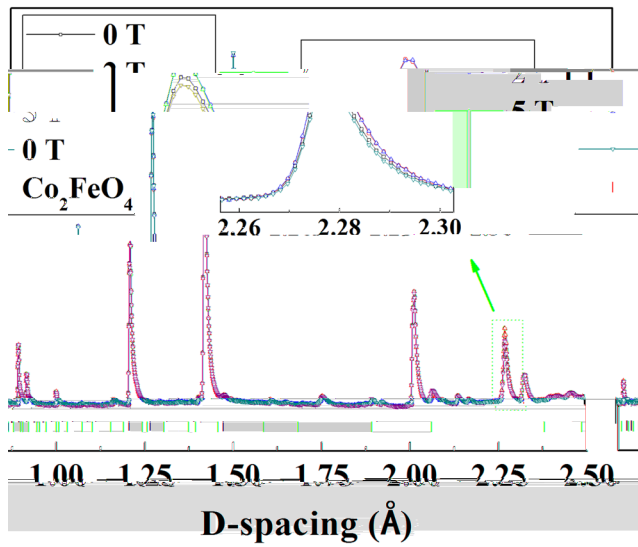


FIG. 4. XRD patterns of Co_2FeO_4 at 0 T and 5 T. The inset shows the schematic of the sample and measurement setup.

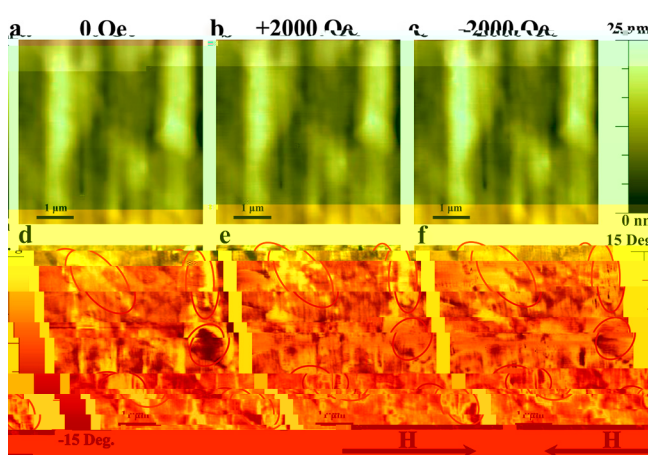
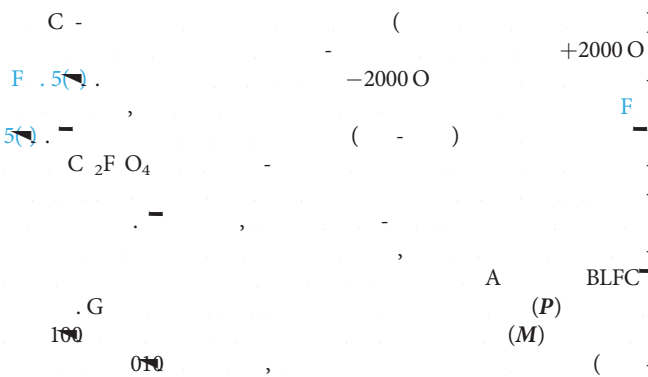


FIG. 5. MFM images of Co_2FeO_4 at 0 Oe, +2000 Oe, and -2000 Oe. The images show the magnetic field dependence of the surface magnetic structure. Scale bars are 1 μm and 25 nm.

$T = P \times M$
 BLFC⁻
 I , A BLFC⁻
 F
 $\text{C}^{3+} \text{O} \text{C}^{3+}, \text{F}^{3+} \text{O} \text{C}^{3+}$
 $\text{F}^{3+} \text{O} \text{F}^{3+}$
 A , C / F
 EM (ED)
 BLFC⁻
 D . M , D . K , D .
 D I H I I N , AL,
 D , O , K.
 A E D F
 G A A (G N . 2/
 0038/20), C (G N . K2015-0602006), N FC (G
 N . 11474138 11834005). A
 E M (EM)
 IND54 N EM
 EM E AME E

DATA AVAILABILITY

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